

# 3<sup>rd</sup> Generation thinQ!<sup>™</sup> SiC Schottky Diode

#### Features

- Revolutionary semiconductor material Silicon Carbide
- Switching behavior benchmark
- No reverse recovery / No forward recovery
- Temperature independent switching behavior
- High surge current capability
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC<sup>1)</sup> for target applications
- Breakdown voltage tested at 20mA<sup>2)</sup>
- Optimized for high temperature operation
- Lowest Figure of Merit  $Q_C/I_F$

#### Product Summary

V <sub>DC</sub>	600	V
Q <sub>C</sub>	4.5	nC
I <sub>F</sub> ; T <sub>C</sub> < 130 °C	4	А

#### PG-T0220-2



#### thinQ! 3G Diode designed for fast switching applications like:

- SMPS e.g.; CCM PFC
- Motor Drives; Solar Applications; UPS

Туре	Package	Marking	Pin 1	Pin 2
IDH04SG60C	PG-TO220-2	D04G60C	С	А

#### **Maximum ratings**

Parameter	Symbol	Conditions	Value	Unit
Continuous forward current	I <sub>F</sub>	7 <sub>C</sub> <130 ℃	4	А
Surge non-repetitive forward current, sine halfwave	I <sub>F,SM</sub>	T <sub>C</sub> =25 °C, t <sub>p</sub> =10 ms	18	
		T <sub>C</sub> =150 °C, <i>t</i> <sub>p</sub> =10 ms	13.5	
Non-repetitive peak forward current	I <sub>F,max</sub>	T <sub>C</sub> =25 °C, t <sub>p</sub> =10 μs	120	
<i>i</i> ²t value	∫i²dt	T <sub>C</sub> =25 °C, t <sub>p</sub> =10 ms	1.8	A <sup>2</sup> s
		T <sub>C</sub> =150 °C, <i>t</i> <sub>p</sub> =10 ms	0.93	
Repetitive peak reverse voltage	V <sub>RRM</sub>	T <sub>j</sub> =25 °C	600	V
Diode dv/dt ruggedness	d <i>v</i> ∕dt	V <sub>R</sub> = 0480 V	50	V/ns
Power dissipation	P <sub>tot</sub>	7 <sub>с</sub> =25 °С	43	W
Operating and storage temperature	T <sub>j</sub> , T <sub>stg</sub>		-55 175	°C
Soldering temperature, wavesoldering only allowed at leads	${\cal T}_{\rm sold}$	1.6mm (0.063 in.) from case for 10s	260	
Mounting torque		M3 and M3.5 screws	60	Ncm



Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

#### Thermal characteristics

Thermal resistance, junction - case	$R_{\mathrm{thJC}}$		-	-	3.5	K/W
Thermal resistance, junction - ambient	$R_{\mathrm{thJA}}$	Thermal resistance, junction- ambient, leaded	-	-	62	

**Electrical characteristics,** at  $T_i$ =25 °C, unless otherwise specified

#### **Static characteristics**

DC blocking voltage	V <sub>DC</sub>	I <sub>R</sub> =0.05 mA, <i>T</i> <sub>j</sub> =25 °C	600	-	-	V
Diode forward voltage	V <sub>F</sub>	I <sub>F</sub> =4 A, <i>T</i> <sub>j</sub> =25 °C	-	2.1	2.3	
		I <sub>F</sub> =4 A, <i>T</i> <sub>j</sub> =150 °C	-	2.8	-	
Reverse current	I <sub>R</sub>	V <sub>R</sub> =600 V, <i>T</i> <sub>j</sub> =25 °C	-	0.3	25	μA
		V <sub>R</sub> =600 V, <i>T</i> <sub>j</sub> =150 °C	-	1.3	270	

#### AC characteristics

Total capacitive charge	Q <sub>c</sub>	V <sub>R</sub> =400 V, <i>I</i> <sub>F</sub> ≤ <i>I</i> <sub>F,max</sub> , d <i>i</i> <sub>F</sub> /d <i>t</i> =200 A/µs,	-	4.5	-	nC
Switching time <sup>3)</sup>	t <sub>c</sub>	$T_{j}=150 \text{ °C}$	-	-	<10	ns
Total capacitance	С	$V_{\rm R}$ =1 V, f=1 MHz	-	80	-	pF
		V <sub>R</sub> =300 V, <i>f</i> =1 MHz	-	10	-	
		V <sub>R</sub> =600 V, <i>f</i> =1 MHz	-	10	-	

#### <sup>1)</sup> J-STD20 and JESD22

<sup>2)</sup> All devices tested under avalanche conditions, for a time periode of 10ms, at 20mA.

 $^{3)}$  t<sub>c</sub> is the time constant for the capacitive displacement current waveform (independent from T<sub>j</sub>, I<sub>LOAD</sub> and di/dt), different from t<sub>rr</sub> which is dependent on T<sub>j</sub>, I<sub>LOAD</sub> and di/dt. No reverse recovery time constant t<sub>rr</sub> due to absence of minority carrier injection.

 $^{4)}$  Under worst case  $Z_{th}$  conditions.

<sup>5)</sup> Only capacitive charge occuring, guaranteed by design.

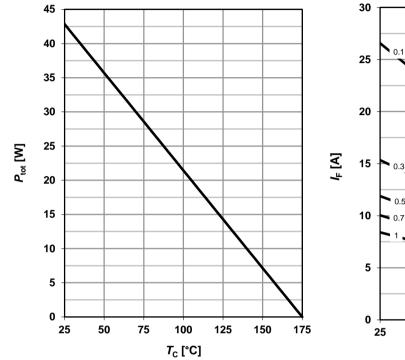


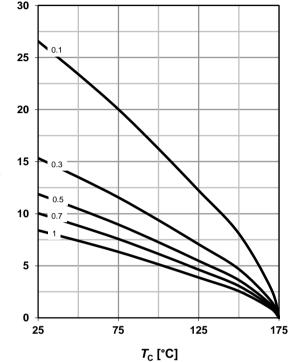
#### **1** Power dissipation

 $P_{tot}=f(T_C)$ ; parameter:  $R_{thJC(max)}$ 

#### 2 Diode forward current

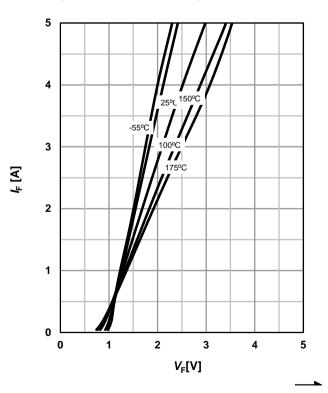
 $I_{\rm F} = f(T_{\rm C})^{4}$ ;  $T_{\rm j} \le 175 \,^{\circ}{\rm C}$ ; parameter:  $D = t_{\rm p}/T$ 





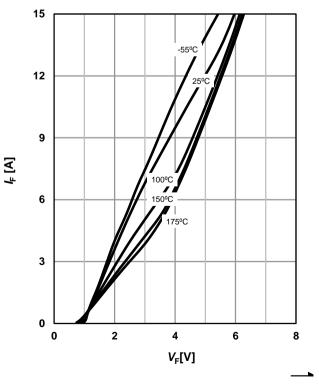
## 3 Typ. forward characteristic

# $I_{\rm F}=f(V_{\rm F}); t_{\rm p}=400 \ \mu {\rm s}; {\rm parameter}:T_{\rm i}$



4 Typ. forward characteristic in surge current mode

 $I_{\rm F}$ =f(V<sub>F</sub>);  $t_{\rm p}$ =400 µs; parameter:  $T_{\rm j}$ 



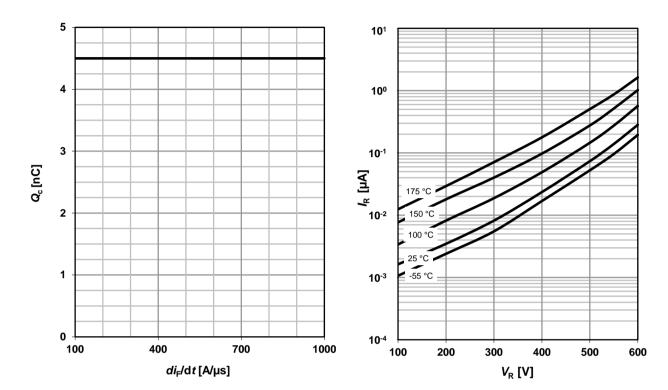


#### 5 Typ. capacitance charge vs. current slope

## 6 Typ. reverse current vs. reverse voltage

 $Q_{C} = f(di_{F}/dt)^{5}; I_{F} \leq I_{F,max}$ 

 $I_{\rm R}$ =f(V<sub>R</sub>); parameter:  $T_{\rm j}$ 

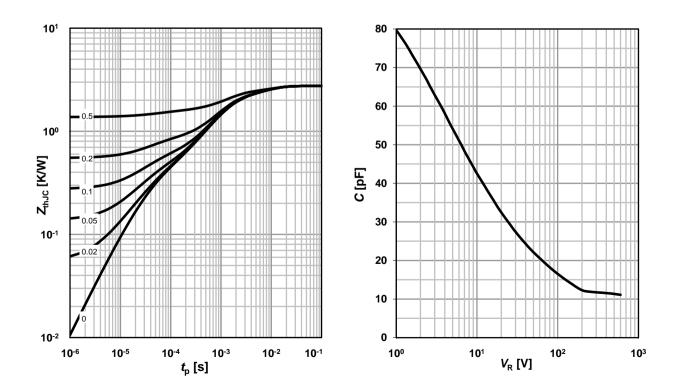


7 Transient thermal impedance

 $Z_{\text{thJC}}=f(t_{p})$ ; parameter:  $D = t_{P}/T$ 

8 Typ. capacitance vs. reverse voltage

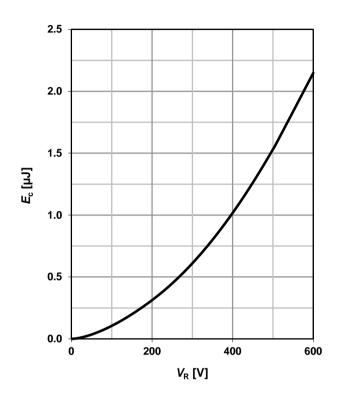
 $C=f(V_R)$ ;  $T_C=25$  °C, f=1 MHz





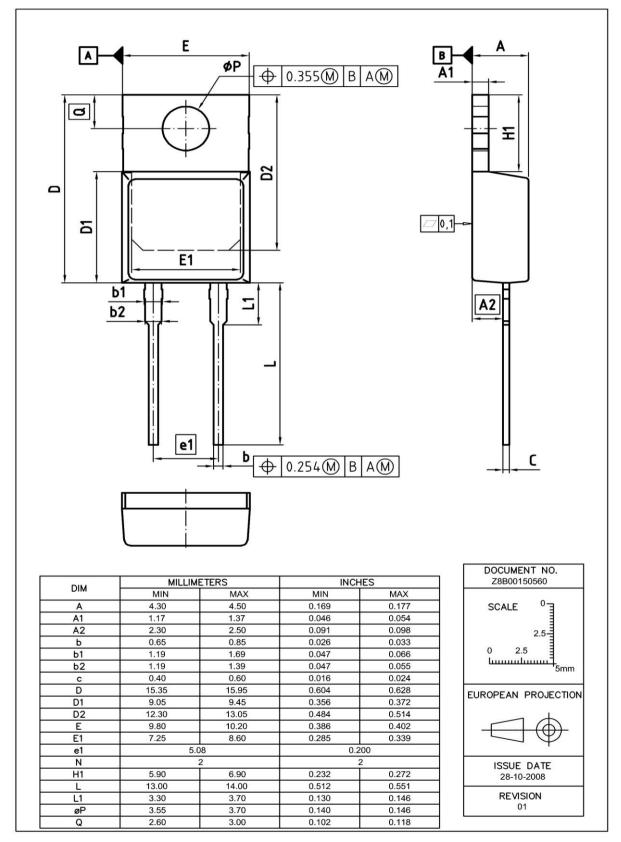
# 9 Typ. C stored energy

 $E_{\rm C}=f(V_{\rm R})$ 





#### PG-TO220-2: Outline



Dimensions in mm/inches





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